

Development of the X-ray polarimeter using CMOS imager: polarization sensitivity of a 1.5 μm pixel CMOS sensor



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Abstract

We are developing an imaging polarimeter using a micro-pixel complementary metal–oxide–semiconductor (CMOS) image sensor and a coded mask to realize polarimetry in the hard X-ray band of 10–30 keV. We call the project cipher (Coded Imaging Polarimetry of High Energy Radiation; Odaka et al. 2020). In this study, we evaluate the polarization sensitivity of a CMOS image sensor with a pixel size of 1.5 μm manufactured by Canon and that with a pixel size of 2.5 μm manufactured by Gpixel. We measure the modulation factor of the sensors. The Obtained modulation factors of the 1.5 μm sensor were $9.52 \pm 0.71\%$ at 10 keV and $17.6 \pm 1.3\%$ at 22 keV, which were higher than that of the sensor with a pixel size of 2.5 μm . These results show that the modulation factor can be improved by using a finer-pixel sensor.

Introduction

- **X-ray polarimetry in astrophysics** is a promising approach to studying the structure of the celestial objects.

- Synchrotron radiation \rightarrow Magnetic field
- Scattering \rightarrow Geometrical structure

- We are developing a hard X-ray imaging polarimeter using a **micro-pixel CMOS sensor**.

The project is called cipher (Coded Imaging Polarimetry of High Energy Radiation; Odaka et al. 2020).

For the details of imaging, see Poster 154 (T. Tamba)

- Photoelectrons tend to be emitted to the polarization angle of incident photons: $(d\sigma/d\Omega) \propto 1 + \cos 2\phi$ (Fig. 1; Heitler 1954).
- Tracking the photoelectrons with a micro-pixel sensor (Fig. 2) \rightarrow information on polarization

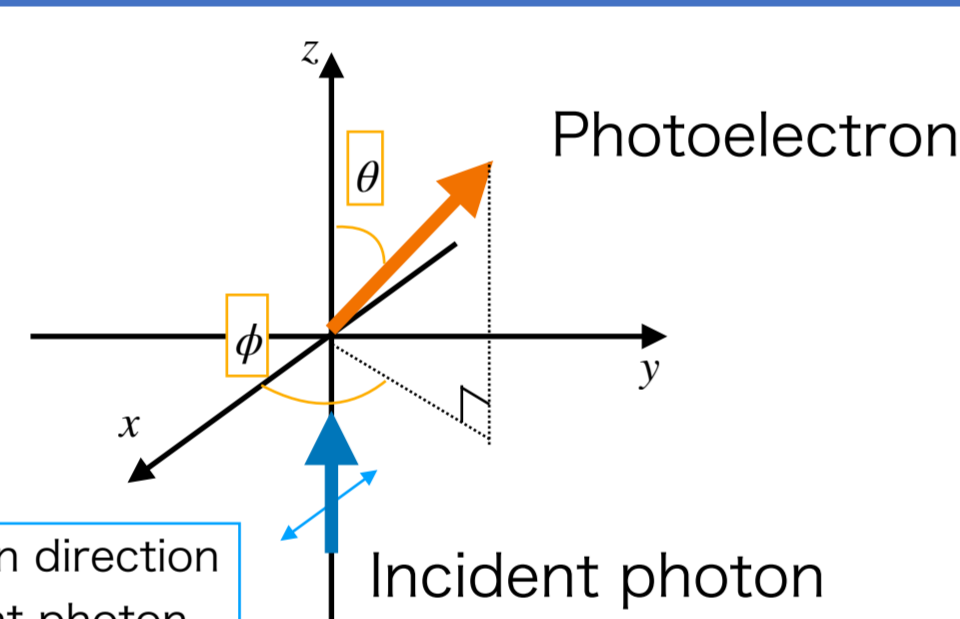
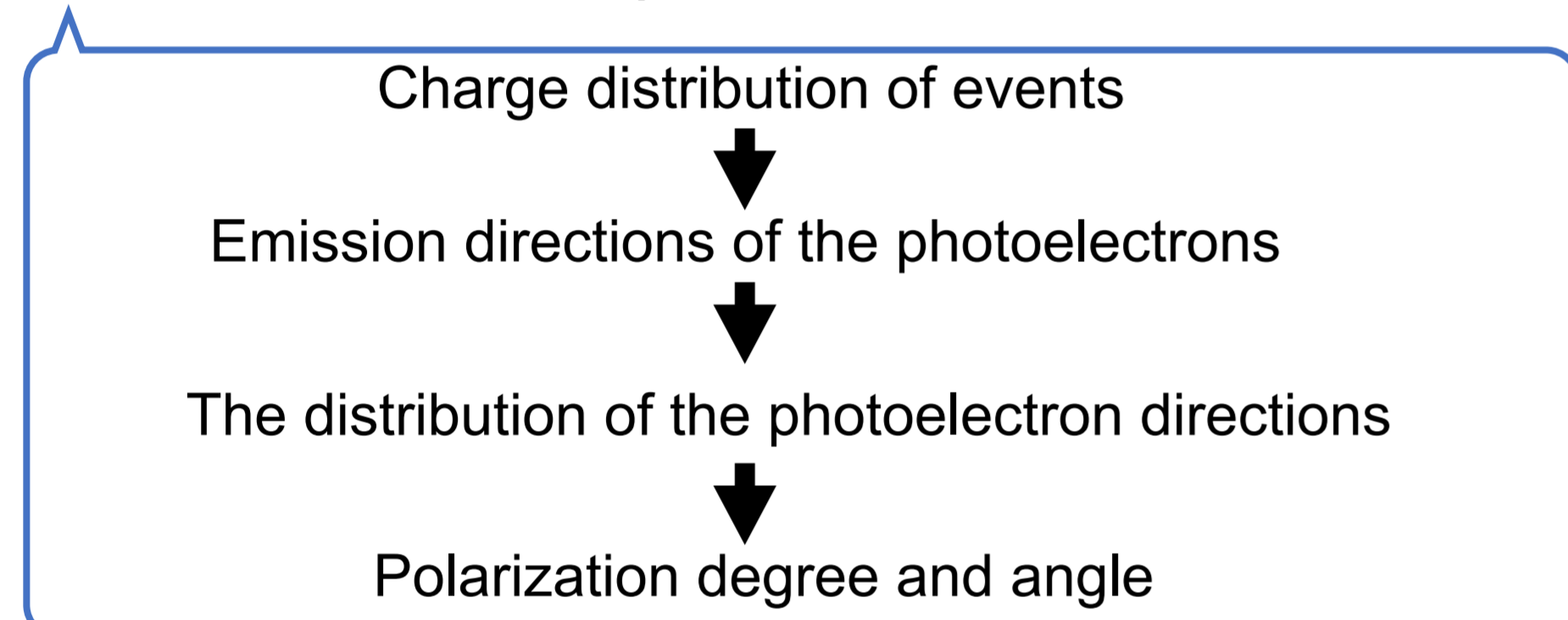


Figure 1: Schematic of photoelectric absorption.

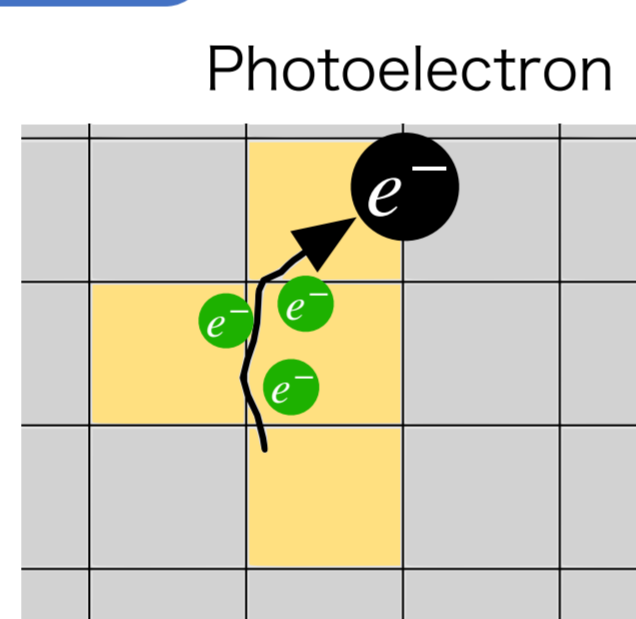


Figure 2: Schematic of the principle of photoelectron tracking.

- Our objective to evaluate **modulation factor (MF) of CMOS sensors**

*MF: modulation amplitude for perfectly polarized incident radiation

MF is an important parameter to calculate the sensitivity for a polarimeter

$$\text{MDP}_{99} \simeq \frac{4.29}{\text{MF}\sqrt{N}} \quad (\text{Kislat et al. 2015}) \quad \text{MDP}_{99}: \text{the minimum detectable polarization on 99\% confidence level}$$

N : the total detection counts

Experiments

Sensors

Table 1: CMOS sensor

	1.5 μm sensor (Canon)	2.5 μm sensor (Gpixel)
Pixel size	1.5 $\mu\text{m} \times 1.5 \mu\text{m}$	2.5 $\mu\text{m} \times 2.5 \mu\text{m}$

- 1.5 μm sensor
 - Smaller pixel size \rightarrow higher photoelectron tracking accuracy
 - \rightarrow **MF is expected to be larger**

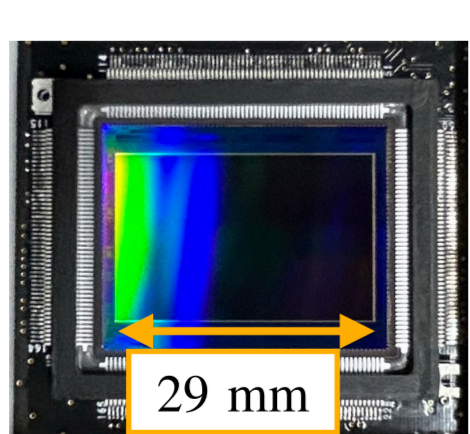


Figure 3: 1.5 μm sensor

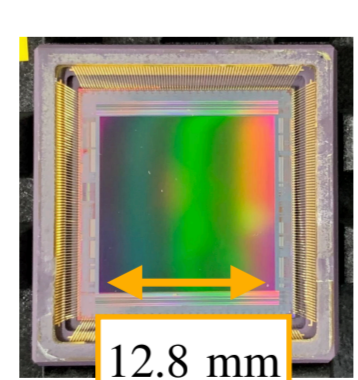


Figure 4: 2.5 μm sensor

Beam experiments to measure MF

- We conducted beam experiment at SPring-8 and PF-KEK to measure MF (Fig. 5)

*SPring-8: the synchrotron radiation facility

*PF-KEK: the Photon Factory of the High Energy Accelerator Research Organization

- Irradiated almost 100% polarized monochromatic beam to the CMOS sensors
- Rotated the stage to change the incident polarization angle
- Acquired data at multiple energies

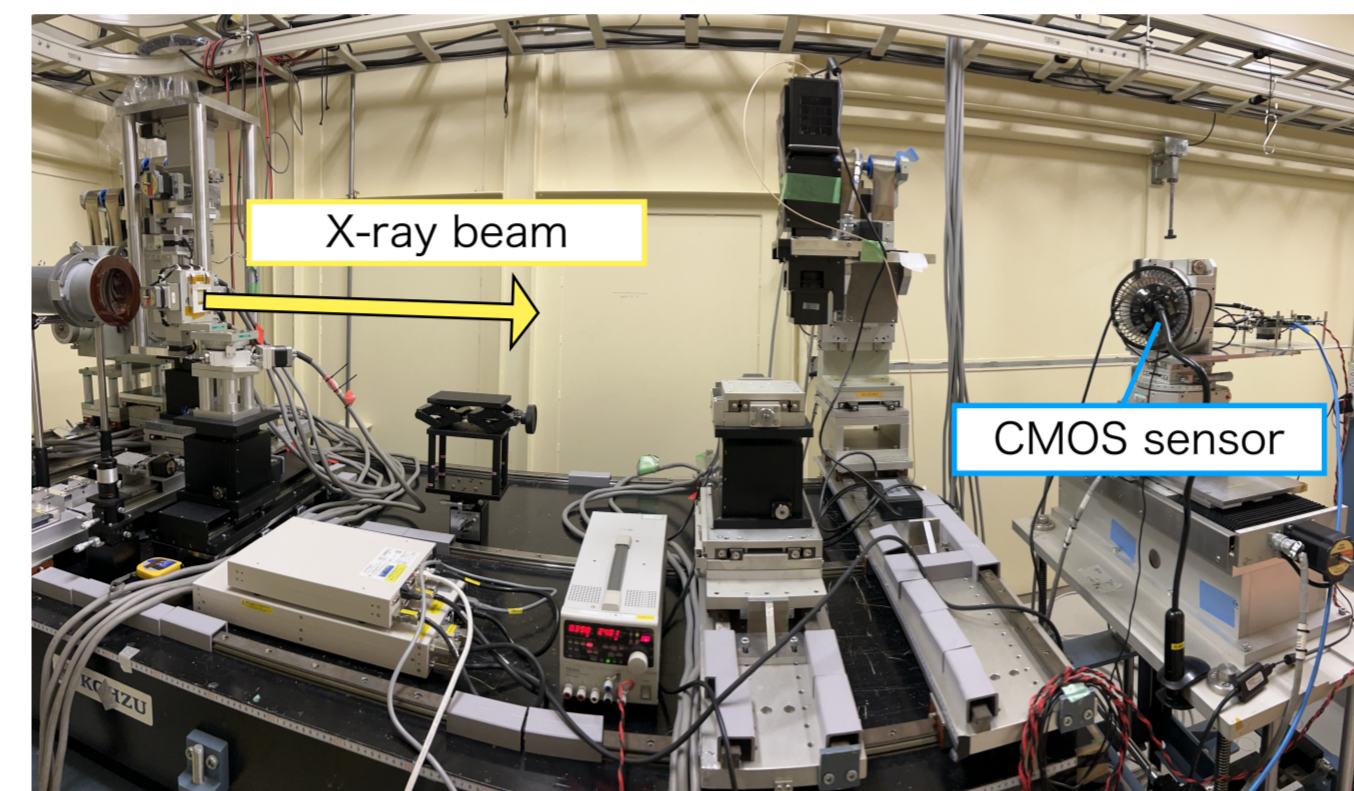
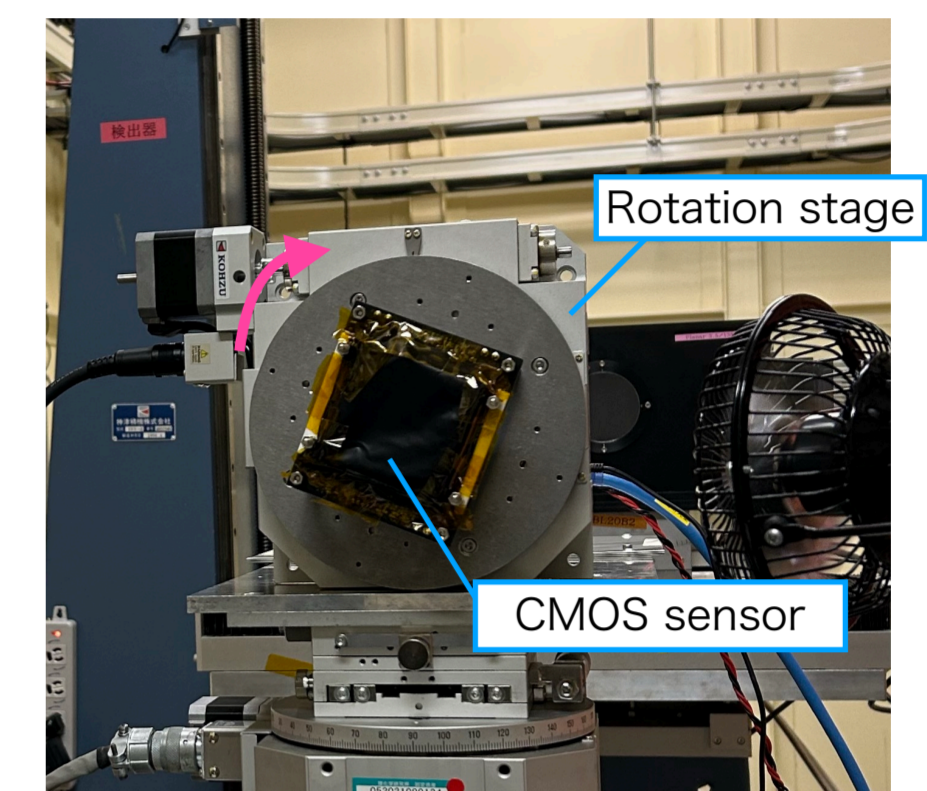


Figure 5: beam experiment



Analysis procedure

- Estimate the emission direction of photoelectron by **maximizing the second moment of the charge distribution, $M_2(\phi)$** (Fig. 6)

$$M_2(\phi) = \frac{\sum_i Q_i x_i^2(\phi)}{\sum_i Q_i} \quad (\text{Bellazzini et al. 2003})$$

* Q_i : charge of the pixel i , $x_i(\phi) = (x_i - x_b)\cos\phi + (y_i - y_b)\sin\phi$ where (x_i, y_i) are the coordinates of the pixel i , and (x_b, y_b) is that of the barycenter

- Correct the distribution of the photoelectron direction (modulation curve; Fig. 7)

- Subtract spurious modulation due to the instrument:
- Recreate the scenario with two sensors positioned at a 45° rotation to correct for differences in modulation due to the incident polarization angle:

- The corrected distributions were fit with sine curve to determine the MF (Fig. 7)

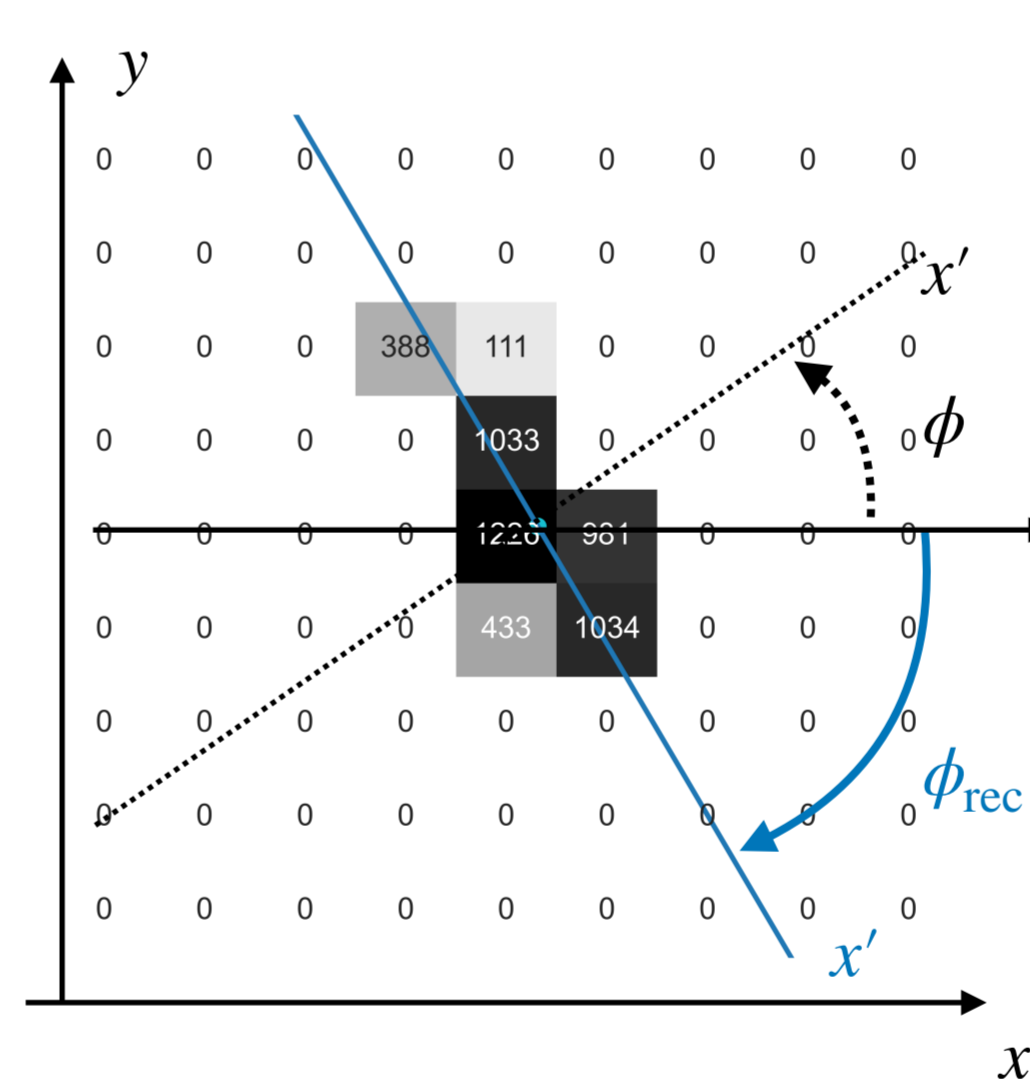


Figure 6: charge distribution and the direction which maximize the second moment

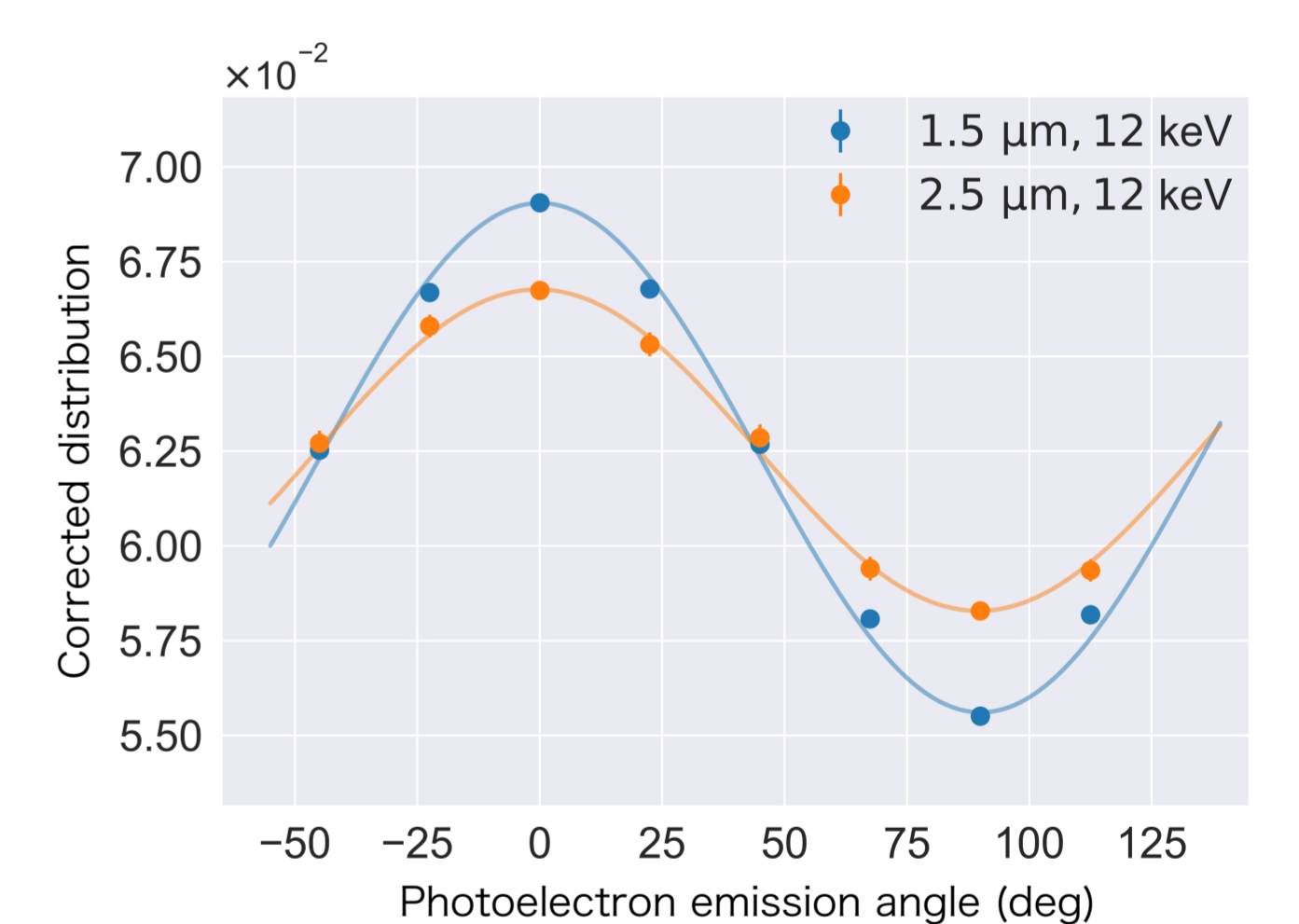


Figure 7: modulation curves

Results

- Utilizing a 1.5 μm sensor resulted in an **improved MF**

Table 2: MF of CMOS sensors

	1.5 μm sensor	2.5 μm sensor
10 keV	$9.52 \pm 0.71\%$	$5.17 \pm 0.39\%$
22 keV	$17.6 \pm 1.3\%$	$14.0 \pm 1.0\%$

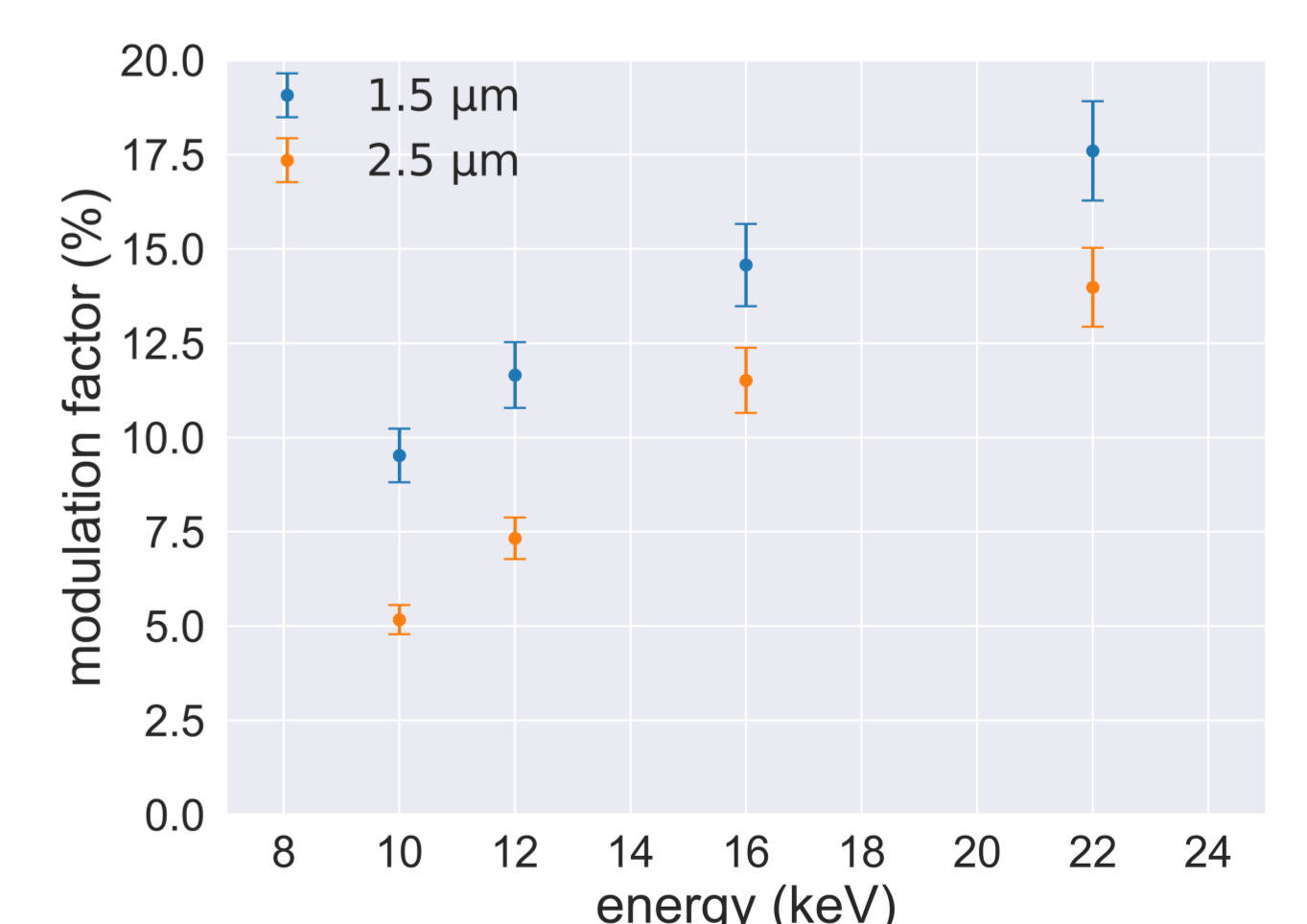


Figure 8: the energy dependence of the MF

The required detection count: 9×10^5 @ 10 keV, 3×10^5 @ 22 keV to detect 5% polarization with 99% confidence using the 1.5 μm sensor

Conclusion

- Utilizing a 1.5 μm sensor resulted in an improved modulation factor (MF) with values of $9.52 \pm 0.71\%$ at 10 keV and $17.6 \pm 1.3\%$ at 22 keV.

Reference

- Bellazzini R., Angelini F., Baldini L., et al., 2003, SPIE, 4843, 383.
- Heitler, W., 1954
- Kislat F., Clark B., Bellicke M., Krawczynski H., 2015, APh, 68, 45.
- Odaka H., Kasuga T., Hatauchi K., et al., 2020, SPIE, 11444, 114445V.